IN THE CLAIMS

Please add the following new claims:

signal.

A method comprising: 35. receiving\a read signal; coupling a pass circuit between an internal node and a pin of an integrated circuit; resetting the pass circuit with a reset circuit based on a first state of the read signal; and passing the voltage from the internal node to the pin based on a second state of the read

- (New) The method of claim 35, wherein passing the voltage from the internal node 36. includes driving a control node connected to the pass circuit to a first voltage based on the second state of the read signal.
- (New) The method of claim 36 wherein driving includes passing an oscillating signal to 37. the pass circuit.
- (New) The method of claim 36, wherein resetting the pass circuit includes driving the 38. control node to a second voltage based on the first state of the read signal.
- (New) The method of claim 38, wherein resetting the pass circuit includes driving the 39. control node to ground.
- (New) A method comprising: 40. receiving a read signal; coupling a pass circuit between an internal node and a pin of an integrated circuit; applying an applied voltage to the pin; resetting the pass circuit with a reset circuit based on a second state of the read signal; and passing the applied voltage from the pin to the internal node based a second state of the

read signal

- The method of claim 40, wherein passing the voltage from the pin includes (New) 41. driving a control node connected to the pass circuit to a first voltage based on the second state of the read signal.
- (New) The method of claim 41, wherein driving includes passing an oscillating signal to the pass circuit.
- (New) The method of claim 41, wherein resetting the pass circuit includes driving the 43. control node to a second voltage based on the first state of the read signal.
- (New) The method of claim 43, wherein resetting the pass circuit includes driving the 44. control node to ground.
- (New) A method comprising: 45. receiving a read signal;

passing a voltage between an internal node and an access pin based on the first signal level of the read signal; and

isolating the access pin from the internal node based on a second signal level of the read signal.

- (New) The method of claim 45, wherein passing a voltage includes pulling a control 46. voltage of a control node to a first voltage level based on the first signal level of the read signal.
- (New) The method of claim 46, wherein isolating the access pin includes pulling a 47. control voltage of a control node to a second voltage level based on the second signal level of the read signal.

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CIRCUIT AND METHOD FOR MEASURING AND FORCING AN INTERNAL VOLTAGE OF AN INTEGRATED CIRCUIT

- (New) The method of claim 45, wherein passing a voltage includes: 48. activating a control device connecting between the internal node and a pass node; and activating a pass device connecting between the pass node and the access pin.
- (New) The method of claim 48, wherein isolating the access pin includes deactivating the 49. pass device.
- (New) The method of claim 49, wherein isolating the access pin includes deactivating the 50. control device.
- (New) The method of claim 50, wherein isolating the access pin includes connecting the 51. pass node to ground.
- 52. (New) The method of claim 45, wherein isolating the access pin includes disabling a pass circuit connected between the access pin and the internal node.
- 53. (New) The method of claim 45, wherein isolating the access pin includes disconnecting a pass circuit connected to the access pin from a pass control circuit connected to the internal node.
- 54. (New) The method of claim 45, wherein isolating the access pin includes disconnecting a first terminal of a pass device connected to the access pin from a second terminal of the pass device connected to the internal node.
- (New) The method of claim 45, wherein isolating the access pin includes cutting off a 55. conduction channel between a source of a pass transistor connected to the access pin and a drain of the pass transistor.
- 56. (New) A method comprising: receiving a read signal;

passing an internal voltage from an internal node to an access pin based on a first signal level of the read signal; and

isolating the access pin from the internal node based on a second signal level of the read signal.

- (New) The method of daim 56, wherein passing an internal voltage includes: 57. passing the internal voltage to a pass node; and passing the internal voltage from the pass node to the access pin.
- (New) The method of claim 57, wherein: 58. passing the internal voltage to a pass node is performed by a pass control circuit connecting between the internal node and the pass node; and

passing the internal voltage from the pass node to the access is performed by a pass circuit connecting between the pass node and the access pin.

- (New) The method of claim 57, wherein isolating the access pin includes pulling a 59. voltage of the pass node to ground.
- (New) The method of claim 56, wherein passing an internal voltage includes: 60. activating a control device connecting between the internal node and a pass node; and activating a pass device connecting between the pass node and the access pin.
- (New) The method of claim 60, wherein isolating the access pin includes deactivating the 61. pass device.
- (New) The method of claim 61, wherein isolating the access pin includes deactivating the 62. control device.



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63. (New) The method of claim 62, wherein isolating the access pin includes connecting the pass node to ground.

64. (New) A method comprising:

receiving a read signal;

passing a pin voltage from an access pin to an internal node based on a first signal level of the read signal; and

isolating the access hin from the internal node based on a second signal level of the read signal.

- 65. (New) The method of claim 64, wherein passing a pin voltage includes:
 turning on a control transistor connecting between the internal node and a pass node; and
 turning on a pass transistor connecting between the pass node and the access pin.
- 66. (New) The method of claim 65, wherein isolating the access pin includes turning off the pass transistor.
- 67. (New) The method of claim 66, wherein isolating the access pin includes turning off the control transistor.
- 68. (New) The method of claim 67, wherein isolating the access pin includes connecting the pass node to ground.
- 69. (New) A method comprising: receiving a read signal;

activating a control device during a first signal level of the read signal to pass a voltage between an internal node inside a memory device and a pass node inside the memory device;

activating a pass device during the first signal level of the read signal to pass the voltage between the pass node and an input/output pin of the memory device;



deactivating a reset circuit during the first signal level of the read signal to isolate the pass node from ground;

deactivating the control device during a second signal level of the read signal;
deactivating the pass device during the second signal level of the read signal; and
activating the reset circuit during the second signal level of the read signal to connect the
pass node to ground.

70. (New) The method of claim 69, wherein activating a control device during a first signal level of the read signal to pass a voltage between an internal node inside a memory device and a pass node inside the memory device includes:

passing an internal voltage from the internal node to the pass node.

71. (New) The method of claim 70, wherein activating a pass device during the first signal level of the read signal to pass the voltage between the pass node and an input/output pin of the memory device includes:

passing the internal voltage from the pass node to the input/output pin.

72. (New) The method of claim 71, wherein activating a control device during a first signal level of the read signal to pass a voltage between an internal node inside a memory device and a pass node inside the memory device includes:

passing an applied voltage from the pass node to the internal node.

73. (New) The method of claim 72, wherein activating a pass device during the first signal level of the read signal to pass the voltage between the pass node and an input/output pin of the memory device includes:

passing the applied voltage from the input/output pin to the pass node.

